

09/686200



10/05/00

Class	Subclass
-------	----------

### ISSUE CLASSIFICATION

PATENT NUMBER

**BEST AVAILABLE COPY**

## U.S. REISSUE Patent Application

O.I.P.E. SCANNED Q.A. 652	O.G. PUBLICATION DATE 5/7/2002	REISSUE PATENT DATE
---------------------------------	-----------------------------------	---------------------

APPLICATION NO. 09/686200	CONT/PRIOR D F	CLASS 324	SUBCLASS 762	ART:UNIT 2858 2829	EXAMINER Nguyen, Vinh
------------------------------	-------------------	--------------	-----------------	--------------------------	--------------------------

## APPLICANTS

Tomomi Momohara

**TITLE**

Probe card having groups of probe needles in a probing test apparatus for testing semiconductor integrated circuits

581 ~~2~~ 249

PTO-2040  
12/99

☐ SURRENDER OF ORIGINAL PATENT \_\_\_\_\_ (Exr. Initials) ORIGINAL PATENT NUMBER \_\_\_\_\_

**ISSUING CLASSIFICATION**

[illegible]

<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>	<b>DRAWINGS</b>		<b>CLAIMS ALLOWED</b>	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner) (Date)		<b>NOTICE OF ALLOWANCE MAILED</b>	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____	_____ (Primary Examiner) (Date)		<b>ISSUE FEE</b>	
<input type="checkbox"/> The terminal ____months of this patent have been disclaimed.			Amount Due	Date Paid
<b>FINAL SPRE REVIEW</b>	_____ (Legal Instruments Examiner) (Date)		<b>ISSUE BATCH NUMBER</b>	
_____ (INITIALS)				

**WARNING:**

**WARNING.** The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-2008  
(Rev. 6/99)

FILED WITH: ☐ DISK (CRF) ☐ FICHE ☐ CD-ROM  
(Attached in pocket on right inside flap)

(FACE)